

#### FEATURES

- High Speed Optocoupler without Base Connection
- GaAIAs Emitter
- Integrated Detector with Photodiode and Transistor
- High Data Transmission Rate: 1 MBit/s
- TTL Compatible
- Open Collector Output
- CTR at  $I_F=16\text{ mA}$ ,  $V_O=0.4\text{ V}$ ,  $V_{CC}=4.5\text{ V}$ ,  $T_A=25^\circ\text{C}$ :  $\geq 19\%$
- Good CTR Linearity Relative to Forward Current
- Field Effect Stable by TRIOS® (Transparent IOn Shield)
- Low Coupling Capacitance
- $dV/dt$ : typ. 10 kV/ $\mu\text{s}$
- Isolation Test Voltage: 5300 VAC<sub>RMS</sub>
- VDE 0884 Available with Option 1
- UL Approval, File #E52744

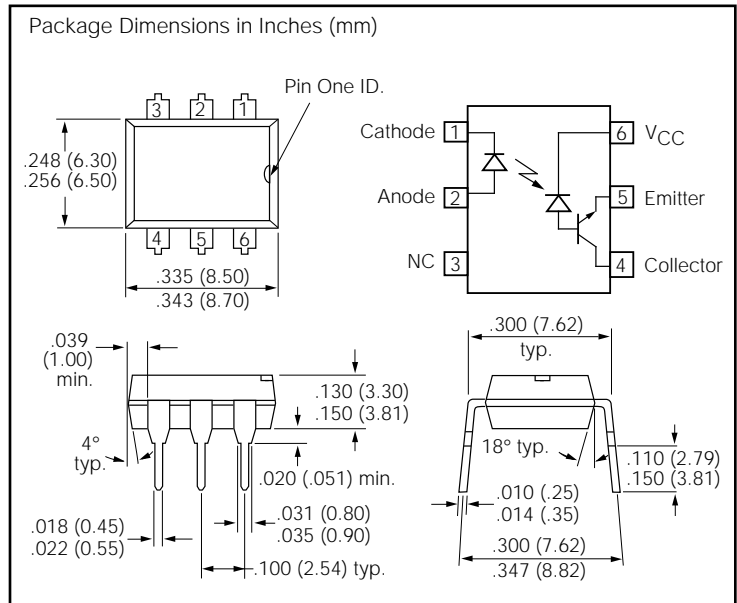
#### APPLICATIONS

- IGBT Drivers
- Data Communications
- Programmable Controllers

#### DESCRIPTION

The SFH636 is an optocoupler with a GaAIAs infrared emitting diode, optically coupled to an integrated photodetector consisting of a photodiode and a high speed transistor in a DIP-6 plastic package. The device is functionally similar to 6N136 except there is no base connection, and the electrical foot print is different. Noise and  $dV/dt$  performance is enhanced by not bringing out the base connection.

Signals can be transmitted between two electrically separated circuits up to frequencies of 2 MHz. The potential difference between the circuits to be coupled should not exceed the maximum permissible reference voltages.



#### Absolute Maximum Ratings

##### Emitter (GaAIAs)

Reverse Voltage.....	3 V
DC Forward Current.....	25 mA
Surge Forward Current.....	1 A
$t_p \leq 1\ \mu\text{s}$ , 300 pulses/sec.	
Total Power Dissipation.....	45 mW

##### Detector (Si Photodiode + Transistor)

Supply Voltage.....	-0.5 to 30 V
Output Voltage.....	-0.5 to 20 V
Output Current.....	8 mA
Total Power Dissipation.....	100 mW

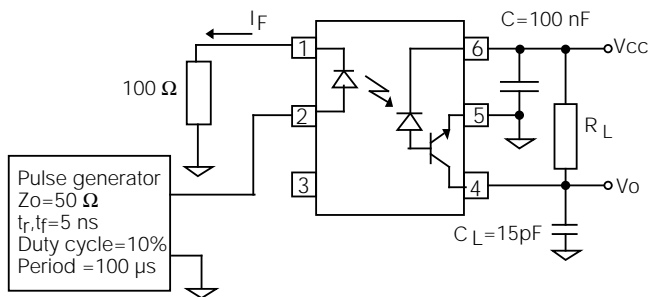
#### Package Insulation

Isolation Test Voltage	
between emitter and detector	
(refer to climate DIN 40046, part 2, Nov. 74) .....	5300 VAC <sub>RMS</sub>
Creepage.....	7 mm min.
Clearance .....	7 mm min.
Comparative Tracking Index	
per DIN IEC 112/VDE0303, part 1 .....	175
Isolation Resistance	
$V_{IO}=500\text{ V}$ , $T_A=25^\circ\text{C}$ .....	$\geq 10^{12}\ \Omega$
$V_{IO}=500\text{ V}$ , $T_A=100^\circ\text{C}$ .....	$\geq 10^{11}\ \Omega$
Storage Temperature Range.....	-55 to +150°C
Ambient Temperature Range.....	-55 to +100°C
Junction Temperature .....	100°C
Soldering Temperature ( $t=10\text{ sec. max.}$ ).....	260°C
Dip soldering: distance to seating plane $\geq 1.5\text{ mm}$	

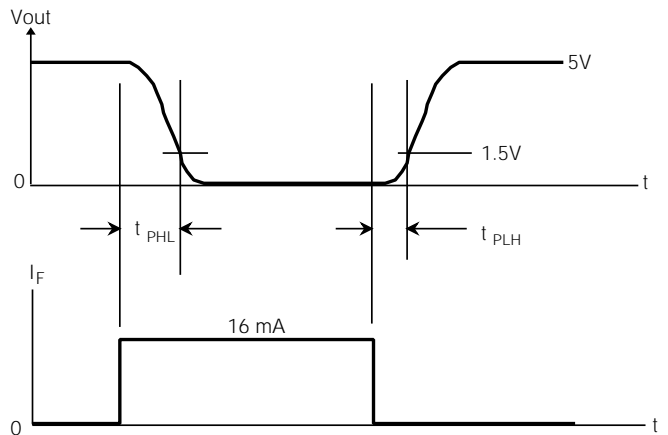
**Characteristics** ( $T_A=0^\circ$  to  $70^\circ\text{C}$ , unless otherwise specified, typical values  $T_A=25^\circ\text{C}$ )

Description	Symbol	Min.	Typ.	Max.	Unit
<b>Emitter (IR GaAlAs)</b>					
Forward Voltage, $I_F=16\text{ mA}$	$V_F$		1.5	1.8	V
Reverse Current, $V_R=3\text{ V}$	$I_R$		0.5	10	$\mu\text{A}$
Capacitance, $V_R=0\text{ V}$ , $f=1\text{ MHz}$	$C_0$		125		pF
Thermal Resistance	$R_{thJA}$		700		$^\circ\text{K/W}$
<b>Detector (Si Photodiode + Transistor)</b>					
Supply Current, Logic High $I_F=0$ , $V_O$ (open), $V_{CC}=15\text{ V}$ , $T_A=25^\circ\text{C}$ $I_F=0$ , $V_O$ (open), $V_{CC}=15\text{ V}$	$I_{CCH}$		0.01	1 2	$\mu\text{A}$
Output Current, Output High $I_F=0$ , $V_O$ (open), $V_{CC}=5.5\text{ V}$ , $T_A=25^\circ\text{C}$ $I_F=0$ , $V_O$ (open), $V_{CC}=15\text{ V}$ , $T_A=25^\circ\text{C}$ $I_F=0$ , $V_O$ (open), $V_{CC}=15\text{ V}$	$I_{OH}$		.003 .01 —	0.5 1 50	$\mu\text{A}$
Capacitance, $V_{CE}=5\text{ V}$ , $f=1\text{ MHz}$	$C_{CE}$		3		pF
Thermal Resistance	$R_{thJA}$		300		$^\circ\text{K/W}$
<b>Package</b>					
Coupling Capacitance	$C_C$		0.6		pF
Coupling Transfer Ratio $I_F=16\text{ mA}$ , $V_O=0.4\text{ V}$ , $V_{CC}=4.5\text{ V}$ , $T_A=25^\circ\text{C}$ $I_F=16\text{ mA}$ , $V_O=0.5\text{ V}$ , $V_{CC}=4.5\text{ V}$	$I_C/I_F$	19 15	30 —		%
Collector Emitter Saturation Voltage $I_F=16\text{ mA}$ , $I_O=2.4\text{ mA}$ , $V_{CC}=4.5\text{ V}$ , $T_A=25^\circ\text{C}$	$V_{OL}$		0.1	0.4	V
Supply Current, Logic Low $I_F=16\text{ mA}$ , $V_O$ open, $V_{CC}=15\text{ V}$	$I_{CCL}$		80		$\mu\text{A}$

**Figure 1. Test set-up**



**Figure 2. Switching time measurement**



Description	Symbol	Min.	Typ.	Max.	Unit
Propagation Delay Time (High–Low) $I_F=16\text{ mA}$ , $V_{CC}=5\text{ V}$ , $R_L=1.9\text{ k}\Omega$ , $T_A=25^\circ\text{C}$	$t_{PHL}$		0.3	0.8	$\mu\text{s}$
Propagation Delay Time (Low–High) $I_F=16\text{ mA}$ , $V_{CC}=5\text{ V}$ , $R_L=1.9\text{ k}\Omega$ , $T_A=25^\circ\text{C}$	$t_{PLH}$		0.3	0.8	$\mu\text{s}$

Figure 3. Common mode transient test

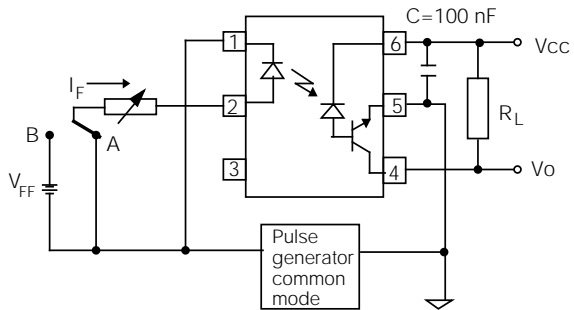
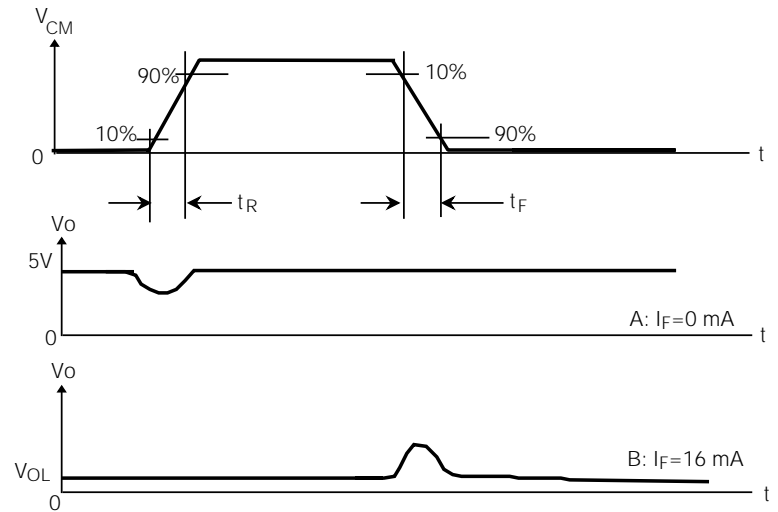


Figure 4. Measurement waveform of CMR



Description	Symbol	Min.	Typ.	Max.	Unit
Common Mode Transient Immunity (High) $I_F=0$ , $V_{CM}=1500\text{ V}_{P-P}$ , $R_L=1.9\text{ k}\Omega$ , $V_{CC}=5\text{ V}$ , $T_A=25^\circ\text{C}$	$CM_H$		10		$\text{kV}/\mu\text{s}$
Common Mode Transient Immunity (Low) $I_F=16\text{ mA}$ , $V_{CM}=1500\text{ V}_{P-P}$ , $R_L=1.9\text{ k}\Omega$ , $V_{CC}=5\text{ V}$ , $T_A=25^\circ\text{C}$	$CM_L$		10		$\text{kV}/\mu\text{s}$